| Search Notes | | | |
|--------------|--|--|--|
| | | | |

| Application/Control No. | Applicant(s)/Patent under Reexamination |
|-------------------------|---|
| 10/047,065 | SAITO ET AL. |
| Examiner | Art Unit |
| Peter Coughlan | 2129 |

| SEARCHED | | | | | |
|----------|----------|----------|----------|--|--|
| | SEARCHED | | | | |
| Class | Subclass | Date | Examiner | | |
| 706 | 1 | 6/1/2006 | PDC | | |
| 706 | 15 | 6/1/2006 | PDC | | |
| 706 | 45 | 6/1/2006 | PDC | | |
| 700 | 1 | 6/1/2006 | PDC | | |
| 700 | 90 | 6/1/2006 | PDC | | |
| 705 | 10 | 6/1/2006 | PDC | | |
| | | | | | |
| | | | | | |
| | | | | | |
| | | | | | |
| | | | | | |
| | | | | | |
| | | | | | |
| | | | | | |

| INTERFERENCE SEARCHED | | | | |
|-----------------------|----------|-------------|----------|--|
| Class | Subclass | Date | Examiner | |
| | | | | |
| _ | | · · · · · · | | |
| | | | | |
| | | | | |
| | | | | |
| | | | | |

| SEARCH NOT (INCLUDING SEARCH | |) |
|---|----------|------|
| | DATE | EXMR |
| East—wavelet, market(s), analysis, trends, rate of change, correlation factor, base functions | 6/1/2006 | PDC |
| IEEE-wavelet, market(s), analysis, trends, rate of change, correlation factor, base functions | 6/1/2006 | PDC |
| Google—Yoshifuru Saito, Yoshihiro Takasuka, Yoshikazu Ishii, wavelet, market(s), rate of change | 6/1/2006 | PDC |
| InventorsYoshifuru Saito, Yoshihiro Takasuka, Yoshikazu Ishii | 6/1/2006 | PDC |
| | | |
| | | |
| | | |
| | | |